

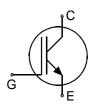
## IGBT Chip in NPT-technology

### Features:

- 1700V NPT technology
- 280µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling
- Qualified according to JEDEC for target applications

### **Recommended for:**

- chip only
- Applications:
- drives
- unves



Chip Type	V <sub>CE</sub>	<i>I</i> <sub>Cn</sub>	Die Size	Package
SIGC185T170R2C	1700V	100A	13.56 x 13.56 mm <sup>2</sup>	sawn on foil

## **Mechanical Parameters**

Mechanical Paramet	612				
Die size		13.56 x 13.56			
Emitter pad size (incl.	gate pad)	See chip drawing m			
Gate pad size		0.757 x 1.48			
Area total		183.87			
Thickness		280	μm		
Wafer size		150	mm		
Max.possible chips pe	er wafer	72	72		
Passivation frontside		Photoimide			
Pad metal		3200 nm AlSiCu			
Backside metal		Ni Ag –system			
Die bond		Electrically conductive epoxy glue and soft solder			
Wire bond		Al, <500µm			
Reject ink dot size		Ø 0.65mm ; max 1.2mm			
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25 < 6 month			
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen o Humidity <25%RH, Temperature 17°C – 25°C, <			

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## **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, $T_{vj}$ =25 °C	V <sub>CE</sub>	1700	V
DC collector current, limited by $T_{vj max}$	I <sub>C</sub>	1)	А
Pulsed collector current, $t_p$ limited by $T_{vj max}^{2}$	I <sub>c,puls</sub>	300	А
Gate emitter voltage	V <sub>GE</sub>	±20	V
Operating junction and storage temperature	$T_{\rm vj,} T_{stg}$	-55 +150	°C
Short circuit data <sup>2</sup> ) <sup>3)</sup> $V_{GE} = 15V$ , $V_{CC} = 1000V$ , $T_{vj} = 150^{\circ}C$	t <sub>SC</sub>	10	μs

<sup>1)</sup> depending on thermal properties of assembly

<sup>2</sup>) not subject to production test - verified by design/characterization

<sup>3)</sup> allowed number of short circuits: <1000; time between short circuits: >1s.

## Static Characteristics (tested on wafer), T<sub>vj</sub> =25 °C

Parameter	Symbol	Conditions	Value			Unit
i arameter	Cymbol		min.	typ.	max.	
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	<i>V</i> <sub>GE</sub> =0V , <i>I</i> <sub>C</sub> =2 mA	1700			
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =100A	2.18	2.6	2.92	V
Gate-Emitter threshold voltage	V <sub>GE(th)</sub>	$I_{\rm C}$ =4.4mA , $V_{\rm GE}$ = $V_{\rm CE}$	4.6	5.5	6.4	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =1700V , V <sub>GE</sub> =0V			3.8	μA
Gate-Emitter leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V , V <sub>GE</sub> =20V			480	nA
Integrated gate resistor	r <sub>G</sub>			2.5		Ω

## Electrical Characteristics (not subject to production test - verified by design / characterization)

Beremeter	Symbol	Conditions	Value			l Init
Parameter	Symbol		min.	typ.	max.	Unit
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =100A, <i>T</i> <sub>vj</sub> =125 °C		3.1		V
Input capacitance	C <sub>ies</sub>	V <sub>CE</sub> =25V, V <sub>GE</sub> =0V, <i>f</i> =1MHz		15000		pF
Reverse transfer capacitance	Cres	$T_{\rm vj}$ =25 °C		700		P.

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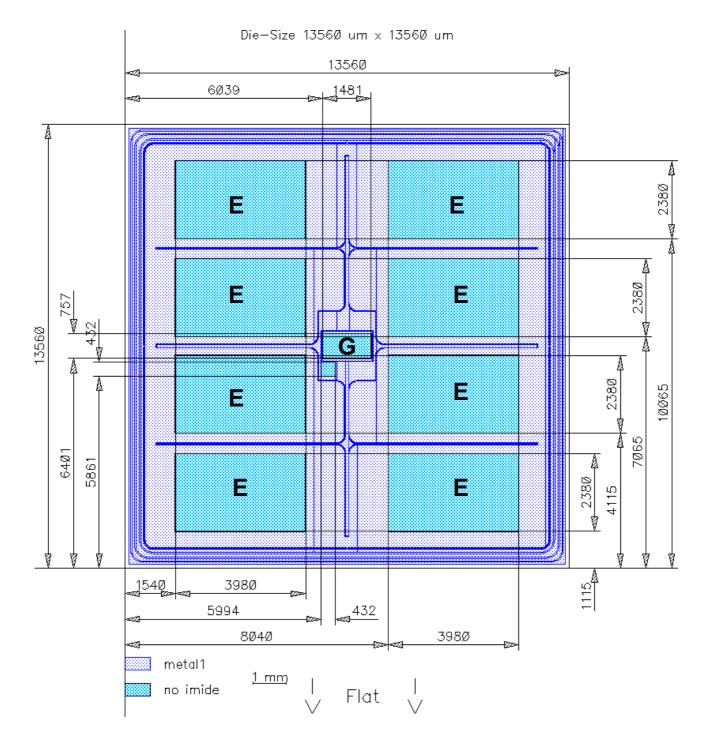
## **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	FZ800R17KF6C_B2 Rev.2.1	04.04.2013
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## **Chip Drawing**



**E** = Emitter

 $\mathbf{G} = \text{Gate}$ 

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#### Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

## **Revision History**

Version	Subjects (major changes since last revision)	Date	
2.2	Operating junction and storage temperature	15.05.2013	

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